INDIAN INSTITUTE OF TECHNOLOGY BOMBAY, POWAI, MUMBAI.

Conductive Atomic Force Microscopy (cAFM)
Central Facility, Department of Electrical Engineering

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Registration Form for External Users

External User Registration No: …………..................... Date: ………………………

1) Name of the User: ……………………………………………………………….....

2) Name of the Institute/Organization: ……………………………………………………
…………………………………………………………………………………………….
(Appropriate letter to be enclosed)

3) Email and Tel No: ………………………………………………………………….

4) Number of samples (Maximum 6): ……………………………………………………….

5) Specifications of samples: Material(s) and Substrate (if any) ……………
……………………………………………………………………….……………..…

6) Has the feasibility of samples discussed with the Operator:
…………………………………………….

7) Mode of AFM (Contact/Tapping/cAFM/MFM/KPFM/PFM):
…………………………………………………

8) Scan size & Resolution required: …………………………………………..………

9) Any other remarks: …………………… …………………………………………....

MATERIAL IS NOT POISONOUS/TOXIC IN ANY WAY (Please provide MSDS data sheet)

We agree to acknowledge the “Conductive Atomic Force Microscopy” CENTRAL FACILITY cAFM of IIT BOMBAY in our Publications/Reports/Thesis in which the data is used with due feedback through email

Signature of the User: ………………………………………………………………..

Note: 1) Samples should be brought by the user at the allotted time and the user should be present while the samples are being examined, 2) Size of the sample should not be more than 12 mm X 12 mm X 2 mm.

For Official Use only:

Date of Experiment:	**Name of Operator:**
Results sent Date:	**Signature of Operator:**